

(12) INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

(19) World Intellectual Property  
Organization  
International Bureau



(43) International Publication Date  
6 January 2005 (06.01.2005)

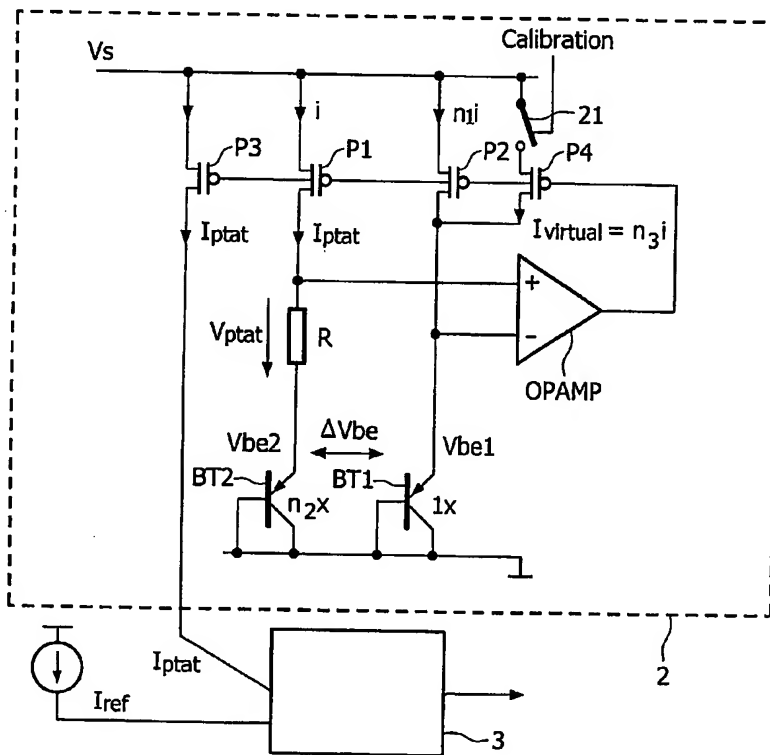
PCT

(10) International Publication Number  
**WO 2005/001405 A1**

- (51) International Patent Classification<sup>7</sup>: **G01K 15/00** (72) Inventors; and  
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Property & Standards GmbH, Weissshausstr. 2, 52066  
Aachen (DE).
- (21) International Application Number:  
PCT/IB2004/050957
- (22) International Filing Date: 22 June 2004 (22.06.2004)
- (25) Filing Language: English (74) Agent: **MEYER, Michael**; Philips Intellectual Property &  
Standards GmbH, Weissshausstr. 2, 52066 Aachen (DE).
- (26) Publication Language: English (81) Designated States (unless otherwise indicated, for every  
kind of national protection available): AE, AG, AL, AM,  
AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN,  
CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI,  
GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE,  
KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD,  
MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG,  
PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM,
- (30) Priority Data:  
03101916.9 27 June 2003 (27.06.2003) EP
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[Continued on next page]

(54) Title: METHOD AND ARRANGEMENT FOR TEMPERATURE CALIBRATION



(57) Abstract: The invention concerns an arrangement on a semiconductor chip for calibrating temperature setting curve having a signal generation unit (2) for providing a first signal ( $I_{ptat1}$ ,  $V_{ptat1}$ ,  $f_{ptat1}$ ), which is proportional to the actual uncalibrated temperature  $T_1$  of the chip. To avoid bringing the chip on a second temperature it is proposed to read a first signal ( $I_{ptat1}$ ,  $V_{ptat1}$ ,  $f_{ptat1}$ ), which is proportional to the actual uncalibrated temperature  $T_1$  of the chip and generate a signal offset ( $I_{virt}$ ,  $V_{virt}$ ,  $f_{virt}$ ), which is combined with the first signal ( $I_{ptat1}$ ,  $V_{ptat1}$ ,  $f_{ptat1}$ ) defining a second signal ( $I_{ptat2}$ ,  $V_{ptat2}$ ,  $f_{ptat2}$ ) and to extract a first actual temperature  $T_1$  from the first signal ( $I_{ptat1}$ ,  $V_{ptat1}$ ,  $f_{ptat1}$ ) and a second uncalibrated temperature  $T_2$  from the second signal ( $I_{ptat2}$ ,  $V_{ptat2}$ ,  $f_{ptat2}$ ).



TN, TR, TT, TZ, UA, UG, US, UZ, VC, VN, YU, ZA, ZM, ZW.

SK, TR), OAPI (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG).

(84) **Designated States** (*unless otherwise indicated, for every kind of regional protection available*): ARIPO (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI,

**Published:**

— with international search report

*For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.*